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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
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## FOREIGN PATENT DOCUMENTS

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	N					
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	υ	Cho et al. Resolution and sensitivity improvement in positron emission tomography by the first interaction point determination, 1991 IEEE Nuclear Science Symposium and Medical Imaging Conference, Vol. 3 (November 2-9, 1991), pp. 1623-1627.
	٧	Comanor et al. Algorithms to identify detector Compton scattering in PET modules, IEEE Transactions on Nuclear Science, Vol. 43, no. 4 (August 1996), pp. 2213-2218.
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	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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